

Enhancement Mode P-Channel Power MOSFET

PDFN5X6/PMOS/-30V/ \pm 20V/-1.6V/-60A/7.5m Ω

Rev0.1





-30V, 7.5mΩ, -60A, P-Channel Enhancement MOSFET

1.Features

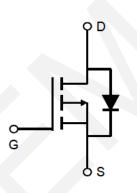
- ◆ -30V MOSFET technology
- Low on-state resistance
- Fast switching
- Vgs±20V
- 100% RG Tested
- 100% UIS Tested

2.Applications

- Power Switching Application
- Load Switching



V _{DS}	R _{DS(on)} Typ.	I _D Max.	
-30V	7.5mΩ @ -10V	CO.A	
	11.6mΩ @ -4.5V	-60A	



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WX075P03PA	075P03	PDFN5X6	5,000	50,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V _{DSS}	-30	V
Gate to Source Voltage	V _{GSS}	±20	V
Drain Current (DC)	ID	-60	А
Drain Current (Pulse), PW≤300μs	I _{DP}	-240	А
Total Dissipation	P _D	30	W
Avalanche Energy, Single Pulsed	E _{AS}	64	mJ
Junction Temperature	Tj	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Junction to Case	Rejc	4.1	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

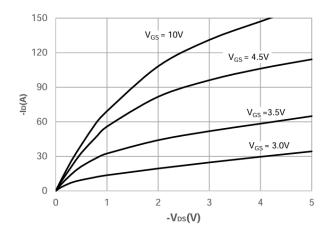
6.Electrical Characteristics at Ta=25°C (Note 3)

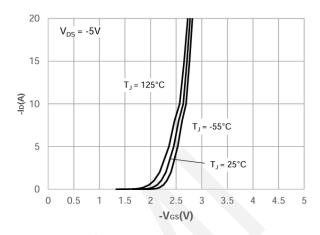
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = -250 \mu A$, $V_{GS} = 0 V$	-30	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} =-30V, V _{GS} = 0V	-	-	-1	μΑ
Gate to Source Leakage Current	Igss	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , I _{DS} =-250µA	-1.0	-1.6	-2.5	V
Static Drain to Source On-State	Б	I _D =-30A, V _{GS} =-10V	1	7.5	9.5	mΩ
Resistance	R _{DS(on)}	I _D =-20A, V _{GS} =-4.5V	-	11.6	15	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	-	2252	-	pF
Output Capacitance	Coss	V _{Ds} =-15V, Frequency=1.0MHz	-	306	-	pF
Reverse Transfer Capacitance	Crss		-	222	-	pF
Turn-ON Delay Time	t _{d(on)}	V_{DD} = -15V, I_{D} = -10A, V_{GS} = -10V, R_{GEN} = 3 Ω	-	6	-	ns
Rise Time	tr		-	2	-	ns
Turn-OFF Delay Time	t _{d(off)}		-	90	-	ns
Fall Time	tf		-	52	-	ns
	Q_g $V_{DS} = -15V$	V _{DS} = -15V,	-	41	-	nC
Total Gate Charge	Qgs	$V_{GS} = 0 \text{ to } -10V,$ $I_D = -10A$	-	7	-	nC
	Q _{gd}		-	10	-	nC
Diode Forward Voltage	V _{FSD}	I _S = -30A, V _{GS} = 0	-0.5	-	-1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

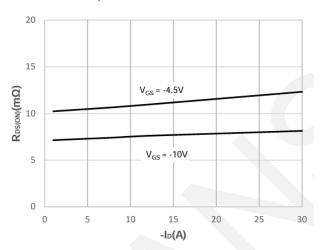


7. Typical electrical and thermal characteristics

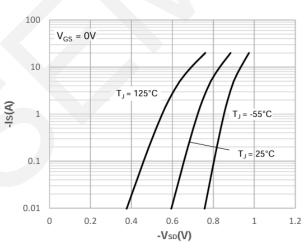




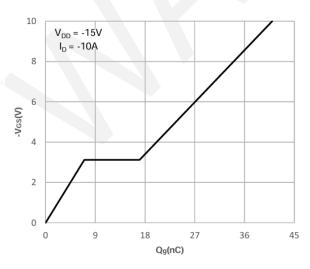
Output Characteristics



Typical Transfer Characteristics

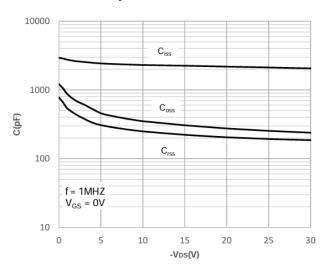


On-resistance vs. Drain Current



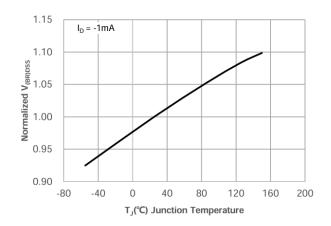
Gate Charge Characteristics

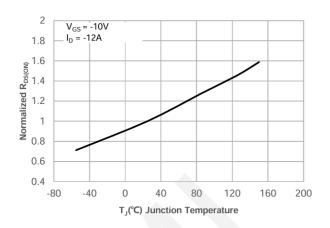
Body Diode Characteristics



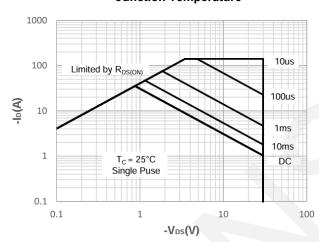
Capacitance Characteristics



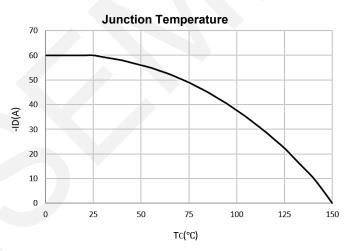




Normalized Breakdown voltage vs. Junction Temperature



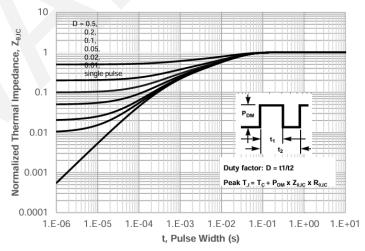
Normalized on Resistance vs.



Maximum Safe Operating Area

Maximum Continuous Drain Current vs.

Case Temperature

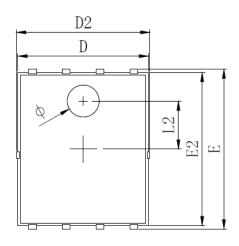


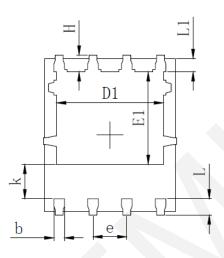
Normalized Maximum Transient

Thermal Impedance



8.Package Dimensions





SYMBOL		MILLIMETER			
SIMDUL	MIN	Тур.	MAX		
A	0. 900	1. 000	1. 100		
A1	0. 254 REF.				
A2		0~0. 05			
D	4. 824	4. 900	4. 976		
D1	3. 910	4. 010	4. 110		
D2	4. 924	5. 000	5. 076		
Е	5. 924	6. 000	6. 076		
E1	3. 375	3. 475	3. 575		
E2	5. 674	5. 750	5. 826		
ь	0. 350 0. 400		0. 450		
e	1.270 TYP.				
L	0. 534	0.686			
L1	0. 424 0. 500		0. 576		
L2	1.800 REF.				
k	1. 190	1. 290	1. 390		
Н	0. 549	0. 625	0. 701		
θ	8°	10°	12°		
ф	1. 100	1. 200	1. 300		
d			0. 100		



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